

HEARING AID COMPATIBILITY

Applicant Name:

LG Electronics MobileComm U.S.A. Inc.
1000 Sylvan Avenue
Englewood Cliffs, NJ 07632
United States

Date of Testing:

11/17/2016

Test Site/Location:

PCTEST Lab, Columbia, MD, USA

Test Report Serial No.:

0Y1611151780.ZNF

FCC ID:

ZNFUS215

APPLICANT:

LG ELECTRONICS MOBILECOMM U.S.A. INC.

Scope of Test:

Audio Band Magnetic Testing (T-Coil)

Application Type:

Certification

FCC Rule Part(s):

CFR §20.19(b)

HAC Standard:

ANSI C63.19-2011

DUT Type:

Portable Handset

Model(s):

LG-US215, LGUS215, US215

Test Device Serial No.:


Pre-Production Sample [S/N: 00490]

C63.19-2011 HAC Category:

T4 (SIGNAL TO NOISE CATEGORY)

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Test results reported herein relate only to the item(s) tested. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. North American Bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.



Randy Ortanez
President







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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.

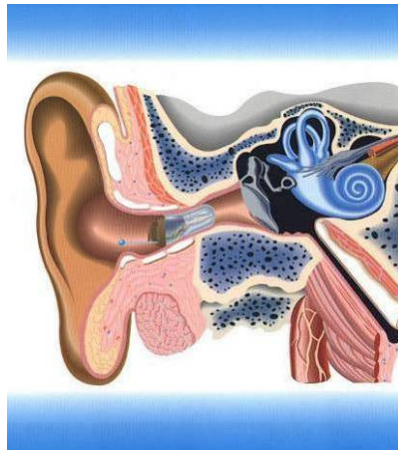




Figure 1-1 Hearing Aid *in-vitu*

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

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2. DUT DESCRIPTION



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Applicant: LG Electronics MobileComm U.S.A. Inc.
 1000 Sylvan Avenue
 Englewood Cliffs, NJ 07632
 United States
Model(s): LG-US215, LGUS215, US215
Serial Number: 00490
HW Version: Rev.1.0
SW Version: US21508i
Antenna: Internal Antenna
HAC Test Configurations: Cellular CDMA, 1013, 384, 777, BT Off, WLAN Off, LTE Off
 PCS CDMA, 25, 600, 1175, BT Off, WLAN Off, LTE Off
DUT Type: Portable Handset

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Voice over Digital Transport OTT Capability	Additional GSM Power Reduction
CDMA	835	VO	Yes	Yes: WIFI or BT	N/A	N/A
	1900					
	EVDO	DT	No	Yes: WIFI or BT	Yes	N/A
LTE (FDD)	700 (B12)	VD ¹	No ²	Yes: WIFI or BT	Yes	N/A
	850 (B5)					
	1700 (B4)					
	1900 (B2)					
1900 (B25)						
WIFI	2450	DT	No	Yes: CDMA or LTE	Yes	N/A
BT	2450	DT	No	Yes: CDMA or LTE	N/A	N/A
Type Transport VO = Voice Only DT = Digital Data - Not intended for CMRS Service VD = CMRS and Data Transport			Notes: 1. The 3GPP VoLTE CMRS service is defined by GSMA in PRD IR.92 for IP Voice Service and Digital Transport. 2. Not tested in accordance with the guidance issued by OET in KDB publication 285076 D02 T-Coil testing for CMRS IP.			

Table 2-1: ZNFUS215 HAC Air Interfaces

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3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be ≥ -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.

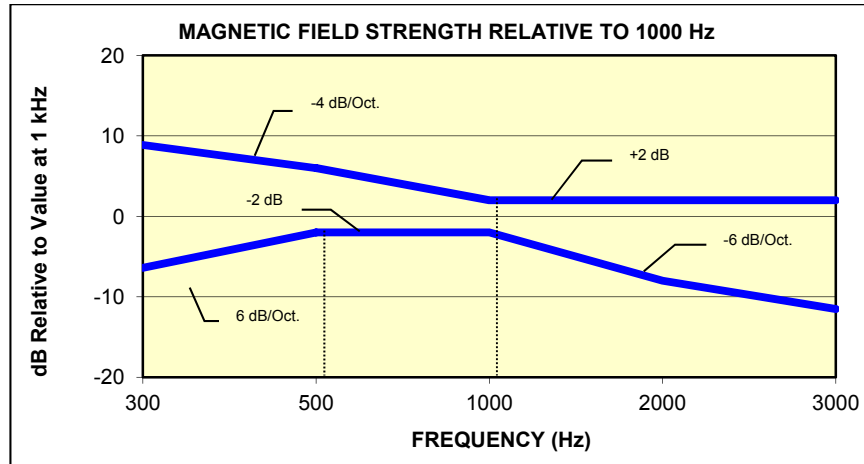


Figure 3-1
Magnetic field frequency response for Wireless Devices with an axial field ≤ -15 dB(A/m) at 1 kHz

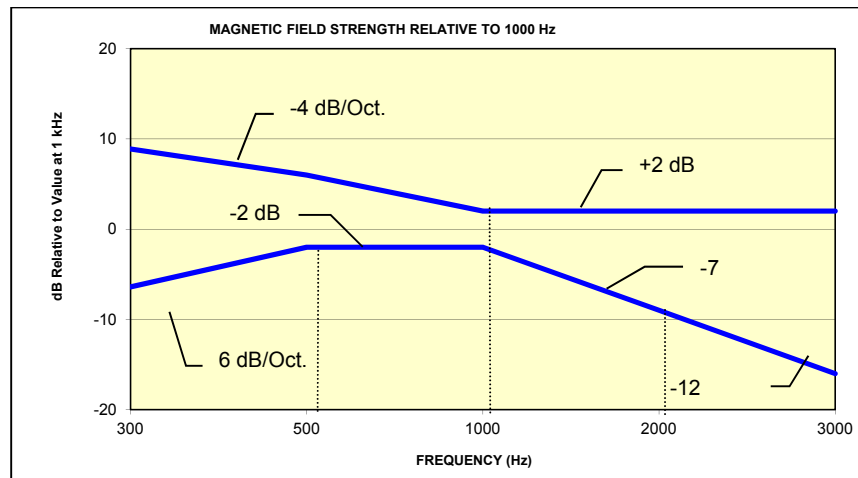


Figure 3-2
Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]
T1	0 to 10 dB
T2	10 to 20 dB
T3	20 to 30 dB
T4	> 30 dB

Table 3-1
Magnetic Coupling Parameters

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4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

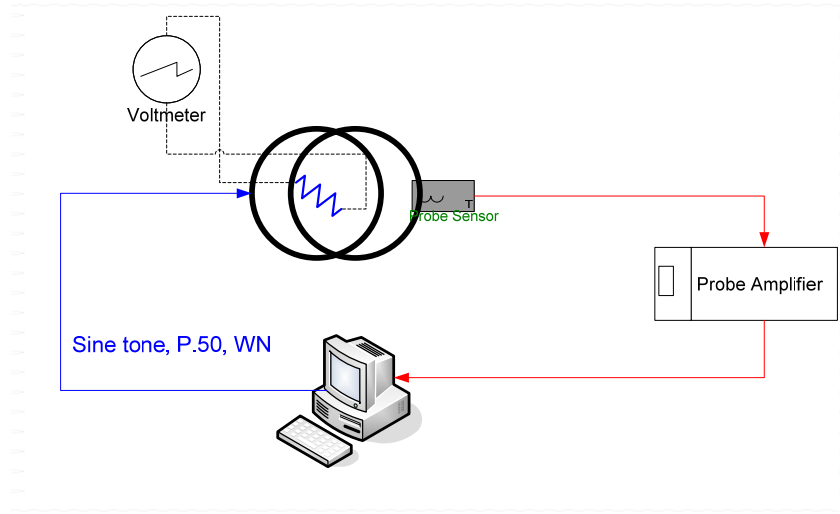


Figure 4-1
Validation Setup with Helmholtz Coil

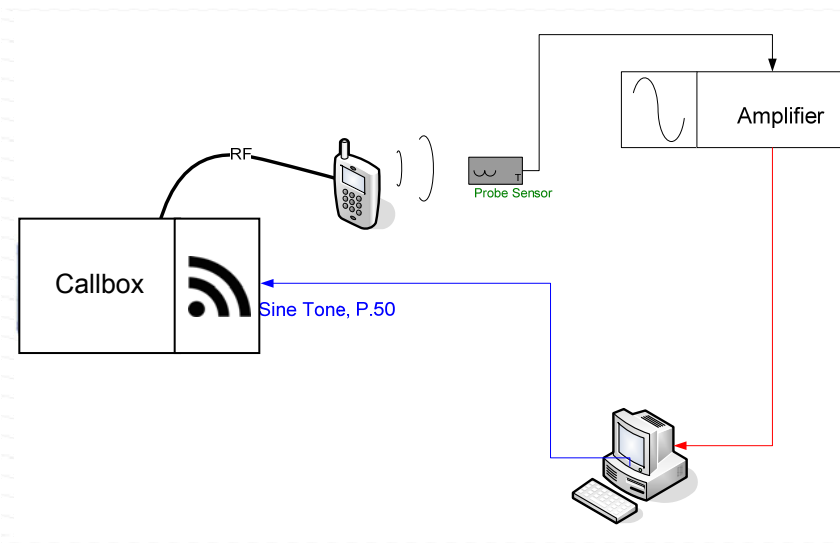




Figure 4-2
T-Coil Test Setup

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II. Scanning Mechanism

Manufacturer: TEM
 Accuracy: ± 0.83 cm/meter
 Minimum Step Size: 0.1 mm
 Maximum speed: 6.1 cm/sec
 Line Voltage: 115 VAC
 Line Frequency: 60 Hz
 Material Composite: Delrin (Acetal)
 Data Control: Parallel Port
 Dynamic Range (X-Y-Z): 45 x 31.75 x 47 cm
 Dimensions: 36" x 25" x 38"
 Operating Area: 36" x 49" x 55"
 Reflections: < -20 dB (in anechoic chamber)

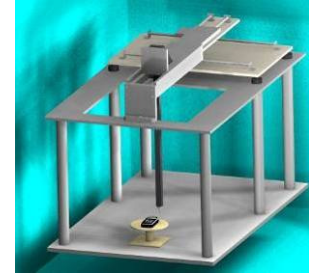


Figure 4-3
RF Near-Field Scanner

III. ITU-T P.50 Artificial Voice

Manufacturer: ITU-T
 Active Frequency Range: 100 Hz – 8 kHz
 Stimulus Type: Male and Female, no spaces
 Single Sample Duration: 20.96 seconds
 Activity Level: 100%

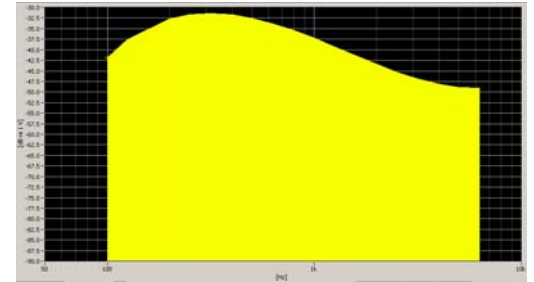


Figure 4-4
Spectral Characteristic of full P.50

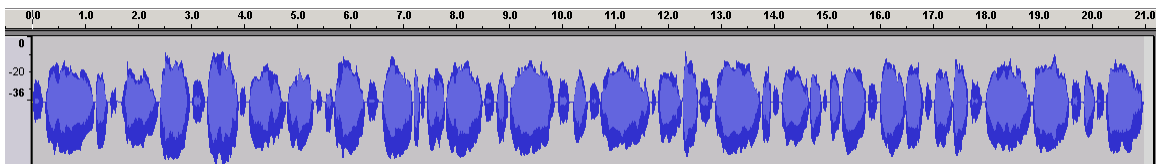


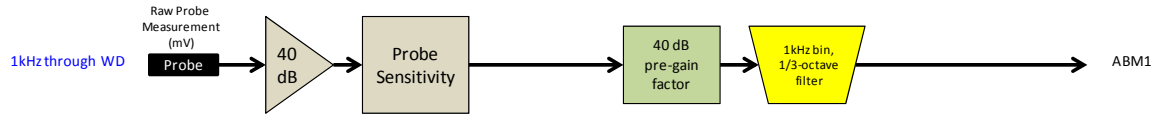


Figure 4-5
Temporal Characteristic of full P.50

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ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:

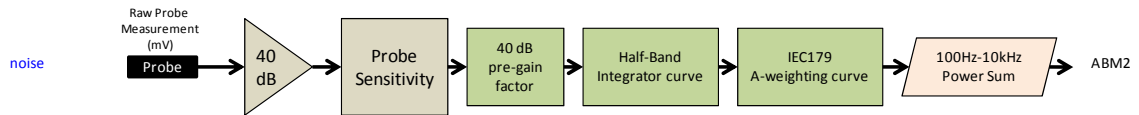


Figure 4-6 Magnetic Measurement Processing Steps

IV. Test Procedure

1. Ambient Noise Check per C63.19 §7.3.1
 - a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - b. "A-weighting" and Half-Band Integration was applied to the measurements.
 - c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

$$-18 - 30 - 10 = -58 \text{ dBA/m}$$

2. Measurement System Validation(See Figure 4-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - b. ABM1 Validation
 The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N\left(\frac{V}{R}\right)}{r\sqrt{1.25^3}}$$



Where H_c = magnetic field strength in amperes per meter

N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.13m; R=10.193Ω and using V=29mV:

$$H_c = \frac{20 \cdot \left(\frac{0.029}{10.193}\right)}{0.13 \cdot \sqrt{1.25^3}} = 0.316 \text{ A/m} \approx -10 \text{ dB(A/m)}$$

Therefore a pure tone of 1kHz was applied into the coils such that 29mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within ± 0.5 dB of the -10dB(A/m) value (see Page 19).

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c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1kHz, between 300 – 3000 Hz using the P.50 signal as shown below:

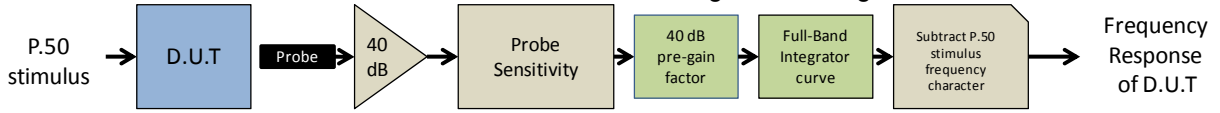




Figure 4-7 Frequency Response Validation

d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 4-1
ABM2 Frequency Response Validation

f (Hz)	HBI, A - Measured (dB re 1kHz)	HBI, A - Theoretical (dB re 1kHz)	dB Var.
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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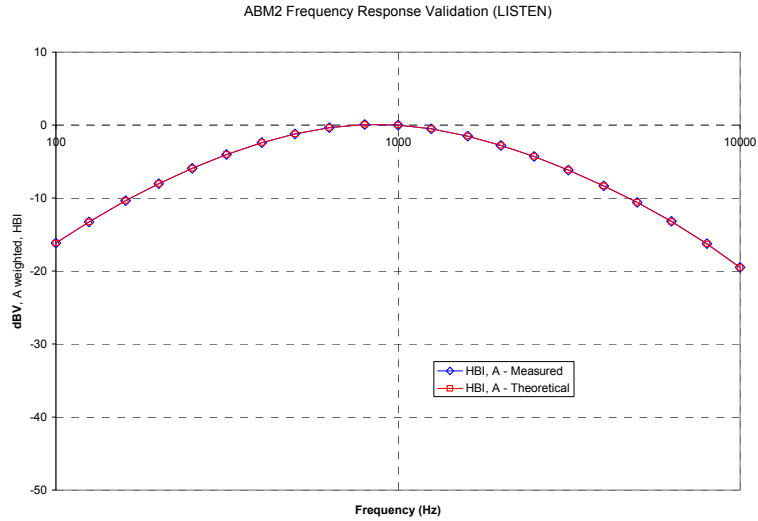


Figure 4-8
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-9). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:

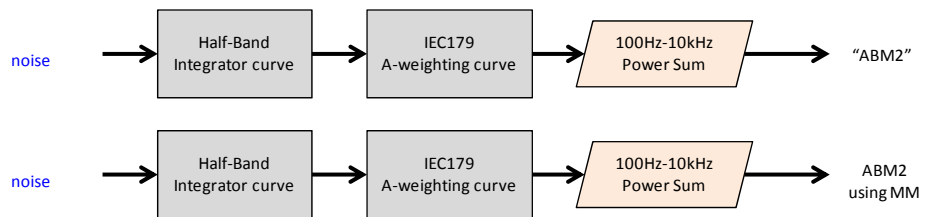


Figure 4-9
ABM2 Validation Block Diagram

The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 4-2
ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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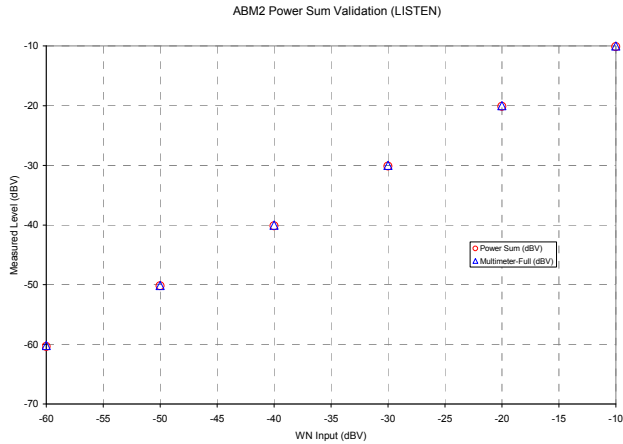


Figure 4-10
ABM2 Power Sum Validation

3. Measurement Test Setup

a. Fine scan above the WD (TEM)

- i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-12, the grid is not to scale but merely a graphical representation of the coordinate system in use):

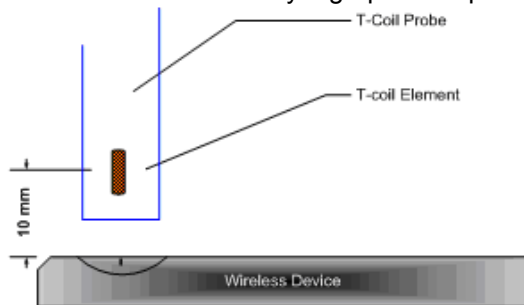


Figure 4-11
Measurement Distance

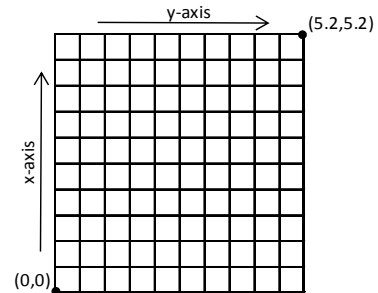


Figure 4-12
Measurement Grid

- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-15 after a T-coil orientation was fully measured with the SoundCheck system.

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- b. Speech Signal Setup to Base Station Simulator
 - i. C63.19 Table 7-1 states audio reference input levels for various technologies:



Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
iDEN™	TDMA (22 and 11 Hz)	-18

The CMU200 audio levels were determined using base station simulator manufacturer calibration procedures resulting in the below corresponding voltages relative to handset test point level (in dBm0):

**Table 4-3
CMU200 Voltage Input Levels for Audio**

dBm0 Ref.	Input Voltage		Notes
3.14 dBm0	1052.0 mV	0.4 dBV	From CDMA2K "DECODER CAL". (What is needed through Encoder for FS)
-18 dBm0	92.260 mV	-20.7 dBV	For 8k Enhanced (Low)

- c. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection
 - i. The device was chosen to be tested in the worst-case ABM2 condition (see Section 5 for more information regarding worst-case configurations for CDMA.)
- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 – 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
 - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-7. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
 - iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.

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c. Signal Quality Index

- i. Ensuring the WD was at maximum RF power, maximum volume, backlight on, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz – 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
- ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
- iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

V. Test Setup

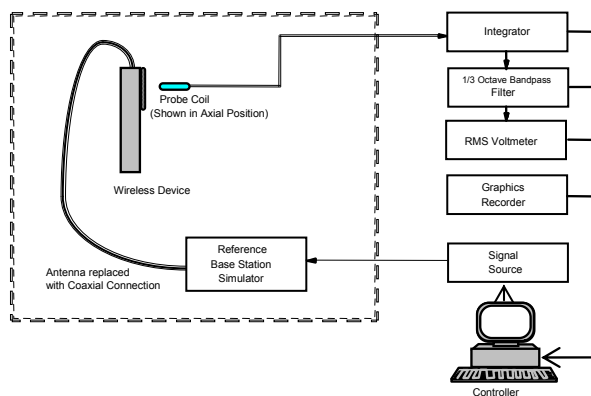


Figure 4-13
Audio Magnetic Field Test Setup

VI. Deviation from C63.19 Test Procedure



Non-conducted RF connection due to inaccessible RF ports.

VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS were tested for T-coil unless otherwise noted. See Table 2-1 for more details regarding which modes were tested.

According to the April 2013 TCB workshop slides, WIFI and other OTT data services are outside the current definition of a managed CMRS service and are currently not required to be evaluated.

VoLTE air interfaces were not tested in accordance with the guidance issued by OET in KDB publication 285076 D02 T-Coil testing for CMRS IP.

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VIII. Wireless Device Channels and Frequencies

1. 2G/3G Modes

The frequencies listed in the table below are those that lie in the center of the bands used for cellular telephony. Low, middle and high channels were tested in each band for FCC compliance evaluation to ensure the maximum emission is captured across the entire band.

**Table 4-4
Center Channels and Frequencies**

Test frequencies & associated channels	
Channel	Frequency (MHz)
Cellular 850	
384 (CDMA)	836.52
PCS 1900	
600 (CDMA)	1880

IX. RF Emission Effect on T-coil Measurements

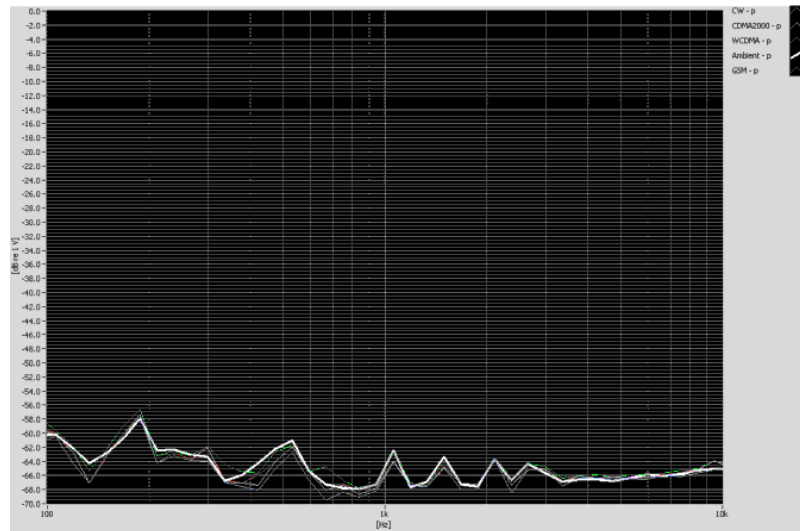




Figure 4-14

High power RF Emissions Effect with HAC Dipole on the T-coil Probe System 10mm between dipole maximum and magnetic probe

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X. Test Flow

The flow diagram below was followed (From C63.19):

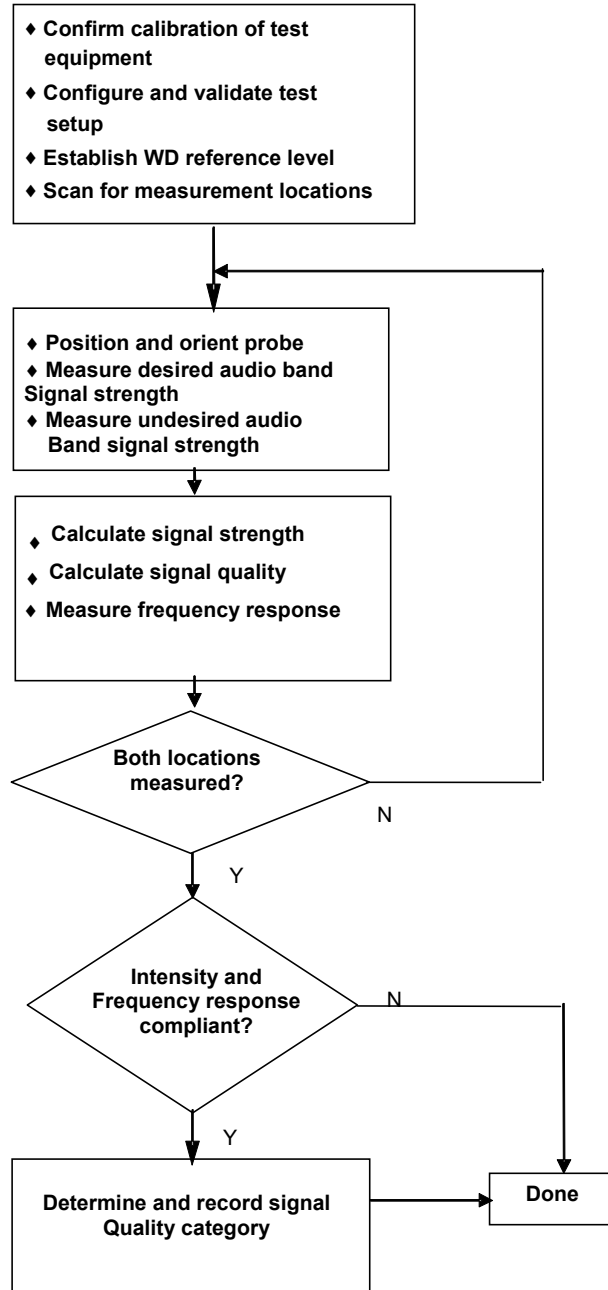




Figure 4-15
C63.19 T-Coil Signal Test Process

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5. FCC 3G MEASUREMENTS

I. CDMA Test Configurations

Radio Configuration 1, Service Option 3 (thick, green data curve) was used for the testing as the worst-case configuration for the handset due to vocoder gating from the EVRC logic. See below plot for ABM noise comparison between operational field service options and radio configurations for a CDMA2000 handset:

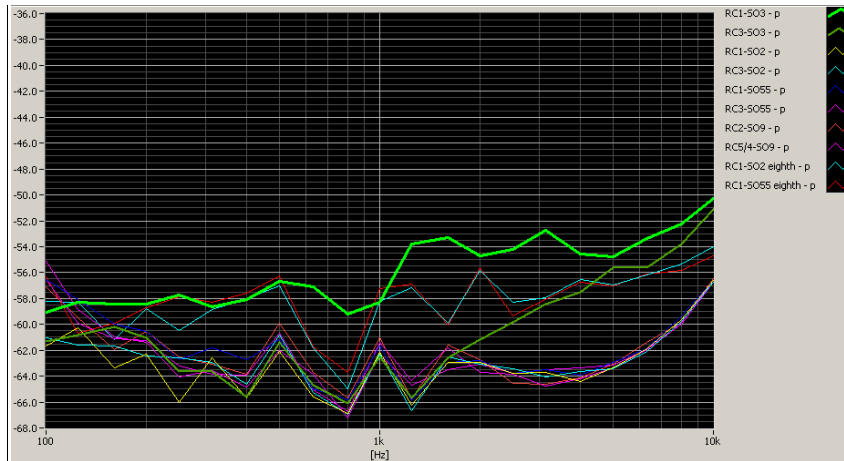


Figure 5-1
CDMA Audio Band Magnetic Noise

Table 5-1
FCC 3G ABM Measurements for ZNFUS215 (CDMA)

Codec Setting:	RC1/SO3	RC3/SO3	RC4/SO3	Orientation	Channel
ABM1 Pre-test (dBA/m)	8.54	8.45	8.32	Radial	777
ABM2 Pre-test (dBA/m) (A-weight, Half-Band Int.)	-23.41	-35.10	-34.26		
S+N/N (dB)	31.95	43.55	42.58		

- Mute on; Backlight on; Max Volume; Max Contrast
- Power Control Bits = "All Up"

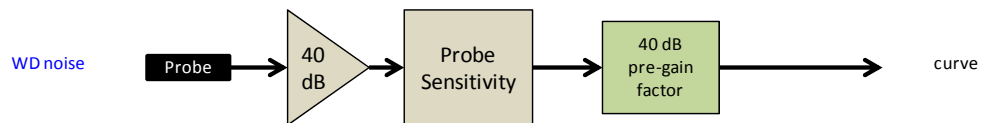


Figure 5-2
Audio Band Magnetic Curve Measurement Block Diagram

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6. TEST SUMMARY

I. T-Coil Test Summary

Table 6-1
Table of Results for CDMA

C63.19 Sec.	Mode	Band	Test Description	Minimum Limit*	Measured	Verdict
				<i>dB(A)/m</i>	<i>dB(A)/m</i>	
8.3.1	CDMA	Cellular	Intensity, Axial	-18	14.6	PASS
8.3.1			Intensity, Radial	-18	8.4	PASS
8.3.4			Signal-to-Noise/Noise, Axial	20	33.6	PASS
8.3.4			Signal-to-Noise/Noise, Radial	20	31.9	PASS
8.3.2			Frequency Response, Axial	0	1.7	PASS
8.3.1	CDMA	PCS	Intensity, Axial	-18	14.0	PASS
8.3.1			Intensity, Radial	-18	8.1	PASS
8.3.4			Signal-to-Noise/Noise, Axial	20	34.6	PASS
8.3.4			Signal-to-Noise/Noise, Radial	20	33.3	PASS
8.3.2			Frequency Response, Axial	0	1.7	PASS

Note: The above summary table represents the worst-case numerical values according to configurations in Table 6-3.

Table 6-2
Consolidated Tabled Results



		Freq. Response Margin		Magnetic Intensity Verdict		FCC SNNR Verdict		FCC Margin (dB)	C63.19-2011 Rating
		Axial	Radial	Axial	Radial	Axial	Radial		
CDMA	Cellular	PASS	NA	PASS	PASS	PASS	PASS	-11.94	T4
	PCS	PASS	NA	PASS	PASS	PASS	PASS		

Note: Result shown is for T-coil category only.

II. Raw Handset Data

Table 6-3
Raw Data Results for CDMA

Mode	Orientation	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	FCC Margin (dB)	C63.19-2011 Rating	Test Coordinates
Cellular	Axial	1013	14.58	-20.80	-64.14	1.73	35.38	20.00	-15.38	T4	2.4, 3.4
		384	14.58	-20.18		1.79	34.76	20.00	-14.76	T4	
		777	14.70	-18.86		1.75	33.56	20.00	-13.56	T4	
	Radial	1013	8.41	-25.08	-65.22	N/A	33.49	20.00	-13.49	T4	2.4, 4.0
		384	8.44	-24.53			32.97	20.00	-12.97	T4	
		777	8.60	-23.34			31.94	20.00	-11.94	T4	
PCS	Axial	25	14.10	-20.54	-64.14	1.69	34.64	20.00	-14.64	T4	2.4, 3.4
		600	14.40	-22.53		1.69	36.93	20.00	-16.93	T4	
		1175	13.99	-20.94		1.65	34.93	20.00	-14.93	T4	
	Radial	25	8.28	-25.03	-65.22	N/A	33.31	20.00	-13.31	T4	2.4, 4.0
		600	8.14	-27.27			35.41	20.00	-15.41	T4	
		1175	8.15	-25.19			33.34	20.00	-13.34	T4	

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III. Test Notes

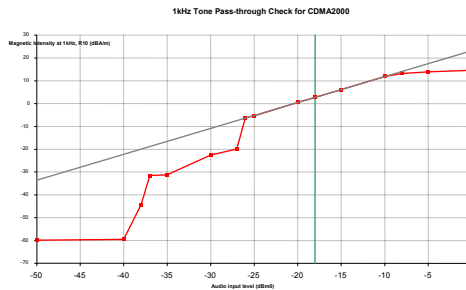
A. General

1. Phone Condition: Mute on; Backlight on; Max Volume; Max Contrast
2. 'Radial' orientation refers to radial transverse.
3. Hearing Aid Mode (**Phone→Call Settings→More→Hearing aids**) was set to ON for Frequency Response compliance

B. CDMA

1. Power Configuration: Power Control Bits = "All Up"
2. Vocoder Configuration: RC1/SO3 (CDMA - EVRC)
3. Speech Signal: ITU-T P.50 Artificial Voice

IV. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -18 dBm0 for CDMA. This measurement was taken in the axial configuration above the maximum location.

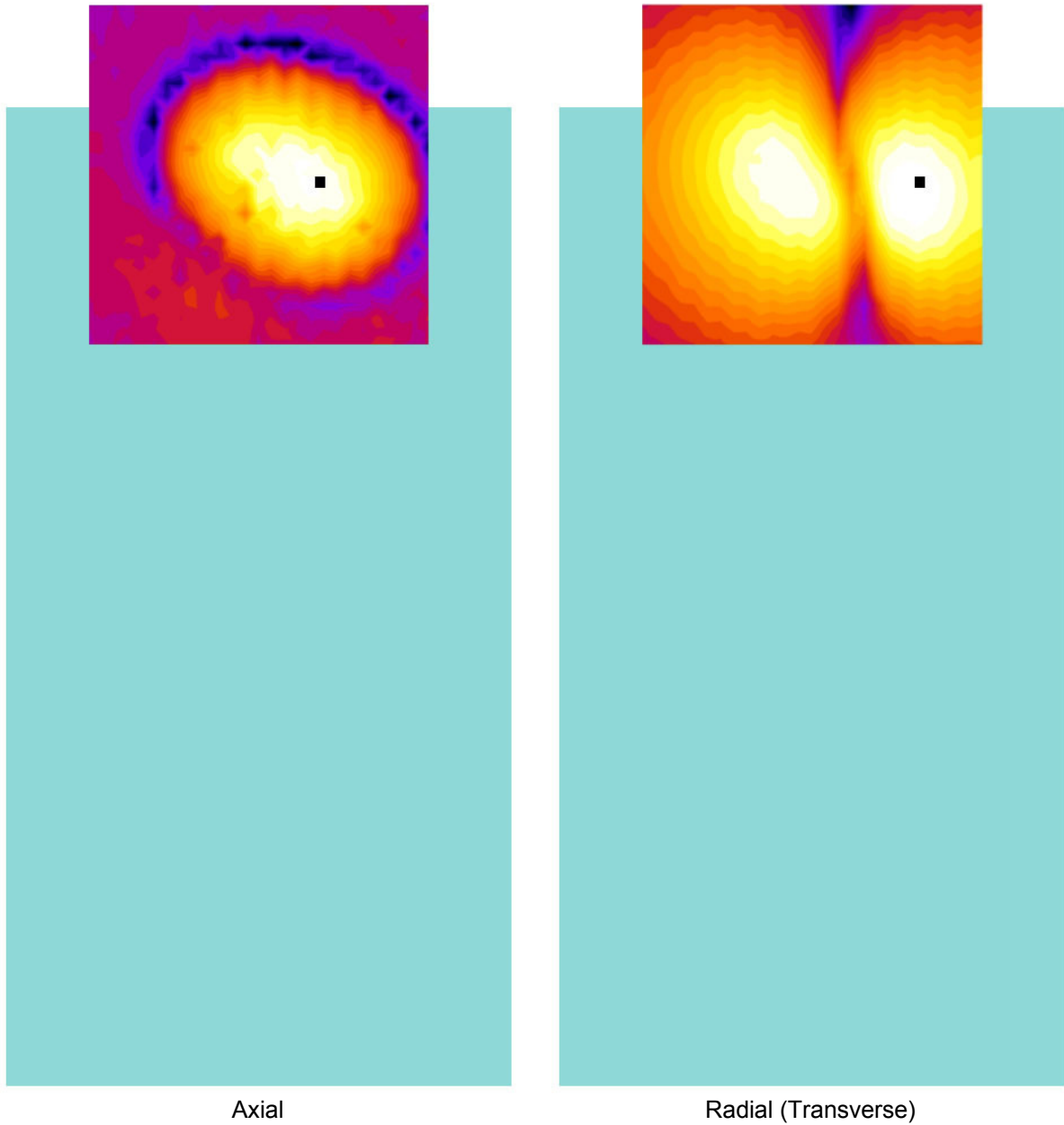
V. T-Coil Validation Test Results

**Table 6-4
Helmholtz Coil Validation Table of Results**

Item	Target	Result	Verdict
Axial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-9.618	PASS
Environmental Noise	< -58 dBA/m	-64.14	PASS
Frequency Response, from limits	> 0 dB	0.60	PASS
Radial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-9.873	PASS
Environmental Noise	< -58 dBA/m	-65.22	PASS
Frequency Response, from limits	> 0 dB	0.80	PASS

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VI. ABM1 Magnetic Field Distribution Scan Overlays



Axial
Radial (Transverse)
Figure 6-1
T-Coil Scan Overlay Magnetic Field Distributions

Notes:

1. Final measurement locations are indicated by a cursor on the contour plots.
2. See Test Setup Photographs for actual WD overlay.

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7. MEASUREMENT UNCERTAINTY



**Table 7-1
Uncertainty Estimation Table**

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, u_c (k=1)						17.7%	0.71
Expanded uncertainty (k=2), 95% confidence level						35.3%	1.31

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.



Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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8. EQUIPMENT LIST

**Table 8-1
Equipment List**

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Listen	SoundConnect	Microphone Power Supply	6/9/2016	Annual	6/9/2017	0899-PS150
Listen	SoundCheck	Acoustic Analyzer System	6/13/2016	Annual	6/13/2017	04-06-5876
Rohde & Schwarz	CMU200	Base Station Simulator	3/29/2016	Annual	3/29/2017	836371/0079
TEM	Helmholtz Coil	Helmholtz Coil	12/22/2015	Annual	12/22/2016	SBI 1052
TEM	Axial T-Coil Probe	Axial T-Coil Probe	6/8/2016	Annual	6/8/2017	TEM-1123
TEM	Radial T-Coil Probe	Radial T-Coil Probe	6/8/2016	Annual	6/8/2017	TEM-1129
TEM		HAC System Controller with Software	N/A	N/A	N/A	N/A
TEM		HAC Positioner	N/A	N/A	N/A	N/A

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9. TEST DATA

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PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil – SN: SBI 1052

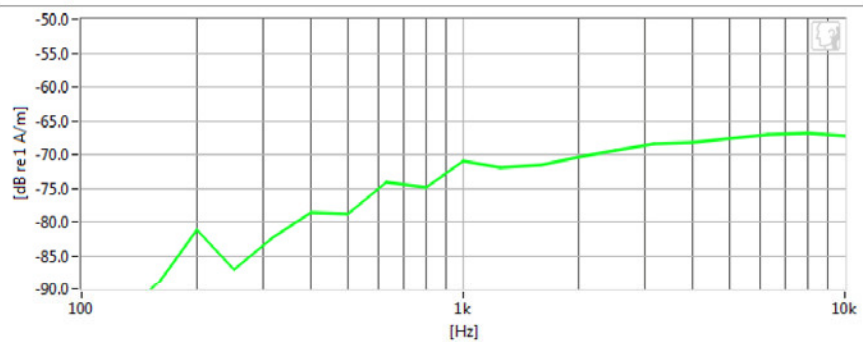
Type: HH Coil
Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

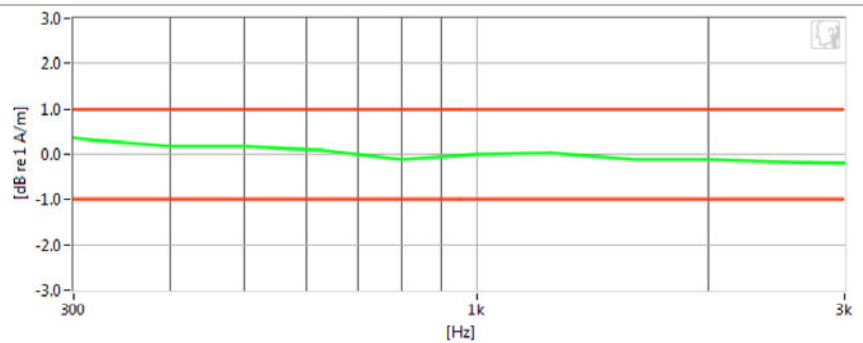
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 06/08/2016
- Helmholtz Coil – SN: SBI 1052; Calibrated: 12/22/2015

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-9.618 dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-64.14 dB	✓	Maximum	-58.0
Frequency Response Margin	600m dB	✓	Tolerance curves	Aligned Data

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FCC ID: ZNFUS215	PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT	LG	Reviewed by: Quality Manager
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PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil – SN: SBI 1052

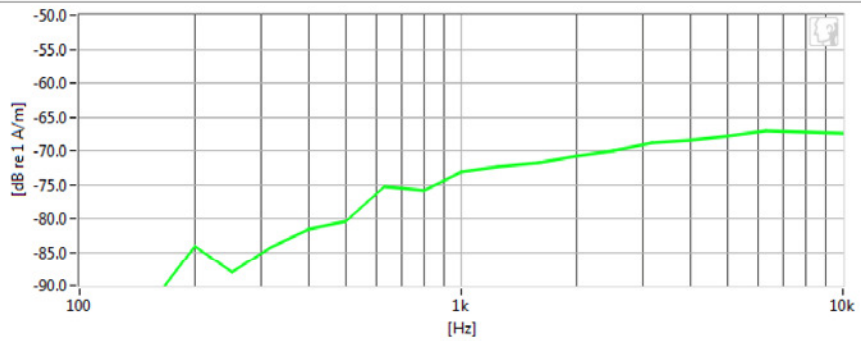
Type: HH Coil
Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

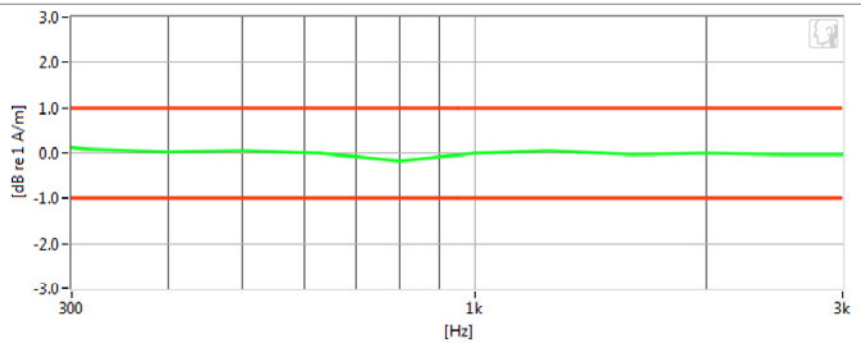
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 06/08/2016
- Helmholtz Coil – SN: SBI 1052; Calibrated: 12/22/2015

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-9.873 dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-65.22 dB	✓	Maximum	-58.0
Frequency Response Margin	800m dB	✓	Tolerance curves	Aligned Data

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DUT: ZNFUS215

Type: Portable Handset
Serial: 00490

Measurement Standard: ANSI C63.19-2011

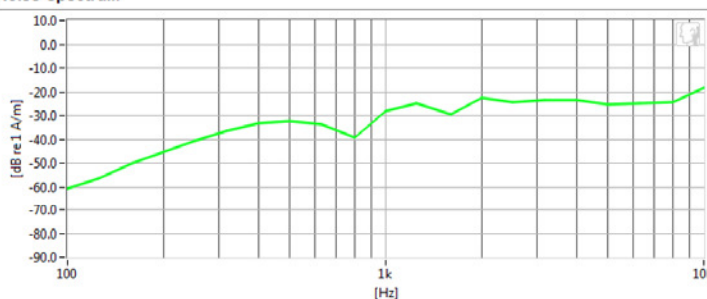
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 06/08/2016

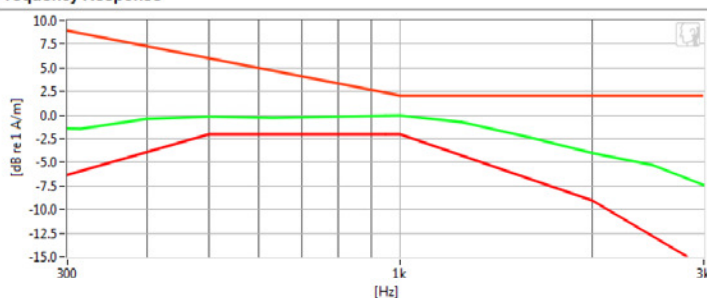
Test Configuration:

- Mode: CDMA Cellular
- Channel: 777
- Speech Signal: ITU-T P.50 Artificial Voice

Noise Spectrum



Frequency Response



Results

ABM1	14.7 dB	✓	Minimum	-18.0
ABM2	-18.86 dB	✓	Maximum	0.0
SNNR	33.56 dB	✓	Minimum	20.0
Aligned Response - P.50	1.75 dB	✓	Tolerance curves	Aligned Data

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PCTEST Hearing-Aid Compatibility Facility

DUT: ZNFUS215

Type: Portable Handset
Serial: 00490

Measurement Standard: ANSI C63.19-2011

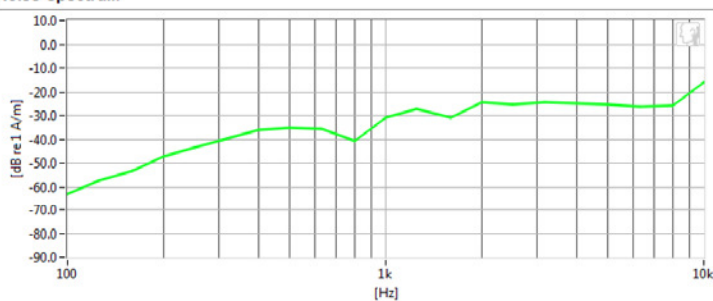
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 06/08/2016

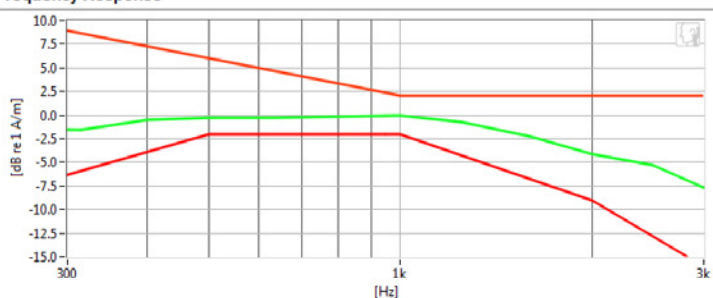
Test Configuration:

- Mode: CDMA PCS
- Channel: 25
- Speech Signal: ITU-T P.50 Artificial Voice

Noise Spectrum





Frequency Response



Results

ABM1	14.1 dB	✓	Minimum	-18.0
ABM2	-20.54 dB	✓	Maximum	0.0
SNNR	34.64 dB	✓	Minimum	20.0
Aligned Response - P.50	1.69 dB	✓	Tolerance curves	Aligned Data

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DUT: ZNFUS215

Type: Portable Handset
Serial: 00490

Measurement Standard: ANSI C63.19-2011

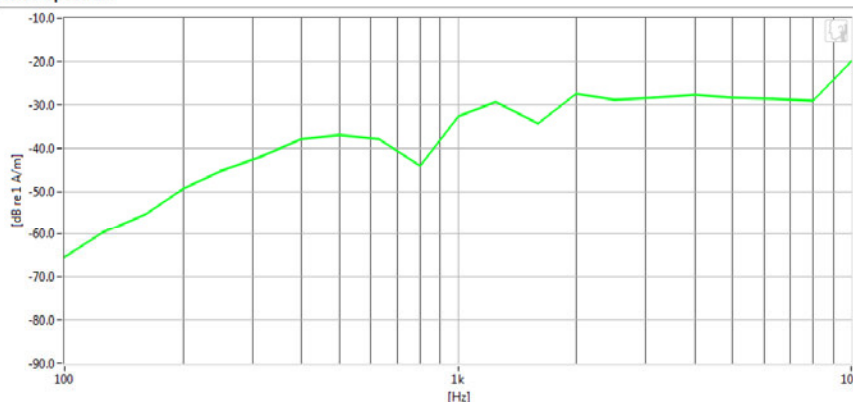
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 06/08/2016

Test Configuration:

- Mode: CDMA Cellular
- Channel: 777

Noise Spectrum



Results

ABM1	8.6 dB	✓	Minimum	-18.0
ABM2	-23.33 dB	✓	Maximum	0.0
SNNR	31.94 dB	✓	Minimum	20.0

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PCTEST Hearing-Aid Compatibility Facility

DUT: ZNFUS215

Type: Portable Handset
Serial: 00490

Measurement Standard: ANSI C63.19-2011

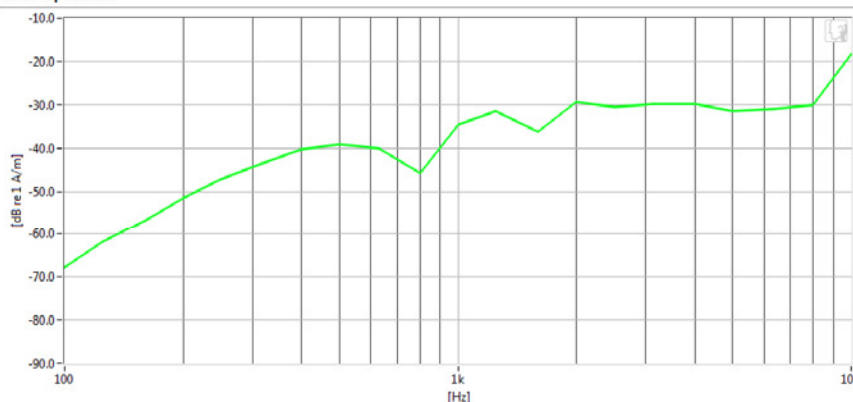
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 06/08/2016

Test Configuration:

- Mode: CDMA PCS
- Channel: 25

Noise Spectrum



Results

ABM1	8.28 dB	✓	Minimum	-18.0
ABM2	-25.03 dB	✓	Maximum	0
SNNR	33.31 dB	✓	Minimum	20

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10. CALIBRATION CERTIFICATES

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West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by: TEM CONSULTING
Model No: AXIAL T COIL PROBE (ID#80582)
Serial No: TEM-1123
Calibration Recall No: 26516

Submitted By:

Customer: ANDREW HARWELL
Company: PCTEST ENGINEERING LAB
Address: 6660-B DOBBIN ROAD
COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. AXIAL T C TEM C

Upon receipt for Calibration, the instrument was found to be:

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.

West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

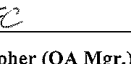
Approved by:

Calibration Date: 08-Jun-16

Certificate No: 26516 - 3

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1




Felix Christopher (QA Mgr.)

ISO/IEC 17025:2005

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.



Calibration Lab. Cert. # 1533.01

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1575 State Route 96, Victor NY 14564

ISO/IEC 17025: 2005



Calibration Lab. Cert. # 1533.01

REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe

for
Model No.: Axial T Coil Probe

Serial No.: TEM-1123

Company : PCTEST Engineering Lab.

I. D. No: 80582

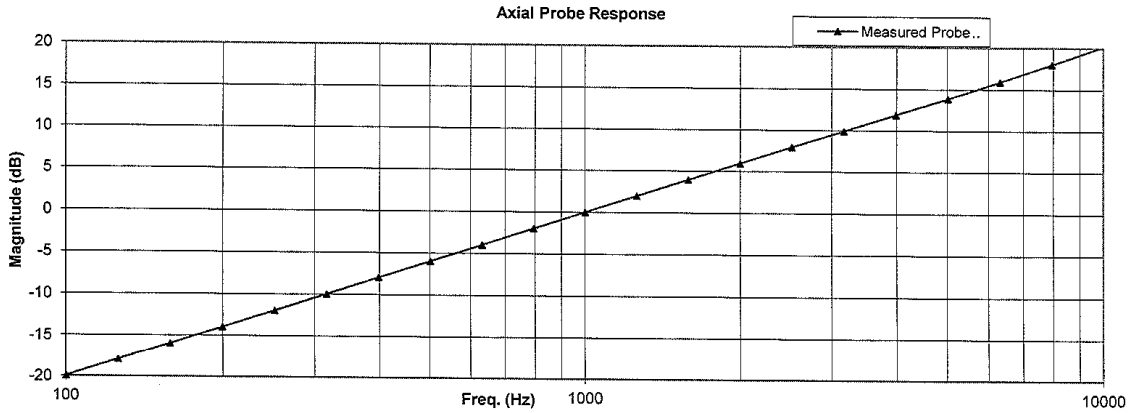
Calibration results:			
Probe Sensitivity measured with Helmholtz Coil			
<i>Helmholtz Coil;</i>			
the number of turns on each coil;	10	No.	Before & after data same: ...X.....
the radius of each coil, in meters;	0.204	m	
the current in the coils, in amperes.;	0.09	A	
<i>Helmholtz Coil Constant;</i>	7.08	A/m/V	Laboratory Environment: Ambient Temperature: 20.3 °C Ambient Humidity: 43.4 % RH Ambient Pressure: 98.3 kPa Calibration Date: 8-Jun-16 Re-calibration Due: 8-Jun-17 Report Number: 26516 -3 Control Number: 26516
<i>Helmholtz Coil magnetic field;</i>	6.20	A/m	
Probe Sensitivity at	1000	Hz.	
was	-60.12	dBV/A/m	
	0.987	mV/A/m	
Probe resistance	895	Ohms	

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NC SL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 8-Jun-2016

Measurements performed by: *Felix Christopher*

Calibrated on WCCL system type 9700

Felix Christopher

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

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HCATEMC_TEM-1123_Jun-08-2016

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Axial T Coil Probe

for
Model No.: Axial T Coil Probe

Serial No.: TEM-1123

Company : PCTEST Engineering Lab.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. dBV/A/m	-60.12		
2.0	Probe Level Linearity	Ref. (0 dB)	6	6.00	
			0	0.00	
			-6	-6.03	
			-12	-12.04	
3.0	Probe Frequency Response	Ref. (0 dB)	100	-19.9	
			126	-17.9	
			158	-15.9	
			200	-14.0	
			251	-12.0	
			316	-10.0	
			398	-8.0	
			501	-6.0	
			631	-4.0	
			794	-2.0	
			1000	0.0	
			1259	2.0	
			1585	4.0	
			1995	6.0	
			2512	7.9	
			3162	9.9	
3981	11.9				
5012	13.9				
6310	15.9				
7943	18.0				
10000	20.2				

Instruments used for calibration:			Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N 36064102	1-Oct-2015	,287708	1-Oct-2016
HP	34401A	S/N 36102471	1-Oct-2015	,287708	1-Oct-2016
HP	33120A	S/N 36043716	1-Oct-2015	,287708	1-Oct-2016
B&K	2133	S/N 1583254	1-Oct-2015	683/284413-14	1-Oct-2016

Cal. Date: 8-Jun-2016



Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

RADIAL T COIL PROBE

Manufactured by: TEM CONSULTING
 Model No: RADIAL T COIL PROBE (ID#80583)
 Serial No: TEM-1129
 Calibration Recall No: 26516

Submitted By:

Customer: ANDREW HARWELL
 Company: PCTEST ENGINEERING LAB
 Address: 6660-B DOBBIN ROAD
 COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. RADIAL T TEM C

Upon receipt for Calibration, the instrument was found to be:

Within (X)

VAH
 06/24/2016

tolerance of the indicated specification. See attached Report of Calibration.

West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Approved by:

Calibration Date: 08-Jun-16

FC

Certificate No: 26516 -2

Felix Christopher (QA Mgr.)

QA Doc. #1051 Rev. 2.0 10/1/01



Certificate Page 1 of 1

ISO/IEC 17025:2005

West Caldwell Calibration Laboratories, Inc.
 uncompromised calibration
 1575 State Route 96, Victor, NY 14564, U.S.A.



Calibration Lab. Cert. # 1533.01

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ISO/IEC 17025: 2005



Calibration Lab. Cert. # 1533.01

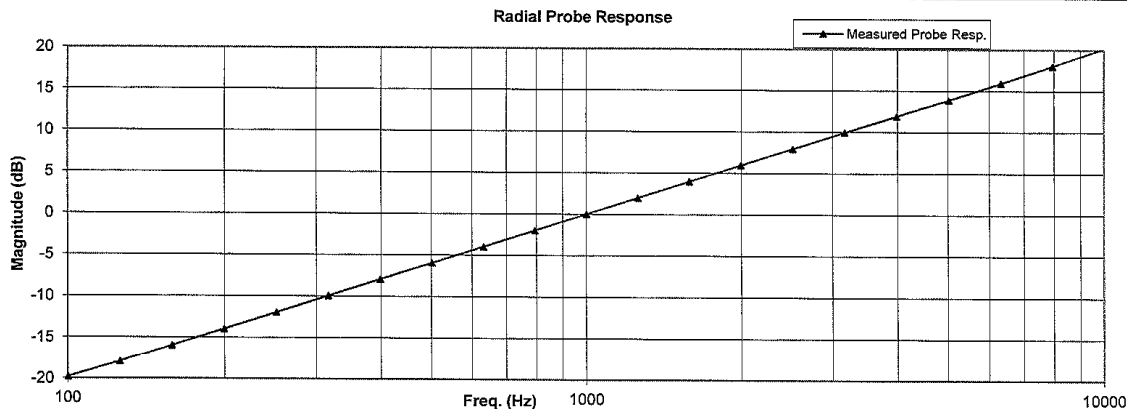
REPORT OF CALIBRATION

TEM Consulting LP Radial T Coil Probe Model No.: Radial T Coil Probe Serial No.: TEM-1129
 Company : PCTEST Engineering Lab. I. D. No: 80583

Calibration results:			
Probe Sensitivity measured with Helmholtz Coil			
<i>Helmholtz Coil;</i>			Before & after data same: ...X.....
the number of turns on each coil;	10	No.	
the radius of each coil, in meters;	0.204	m	Laboratory Environment:
the current in the coils, in amperes.;	0.09	A	Ambient Temperature: 20.3 °C
<i>Helmholtz Coil Constant;</i>	7.08	A/m/V	Ambient Humidity: 43.4 % RH
<i>Helmholtz Coil magnetic field;</i>	6.22	A/m	Ambient Pressure: 98.3 kPa
			Calibration Date: 8-Jun-16
Probe Sensitivity at	1000	Hz.	Re-calibration Due: 8-Jun-17
was	-60.57	dBV/A/m	Report Number: 26516 -2
	0.937	mV/A/m	Control Number: 26516
Probe resistance	899	Ohms	

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14
 The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.
 Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure : **Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC**
 Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 8-Jun-2016 Measurements performed by: *Felix Christopher*
 Calibrated on WCCL system type 9700 **Felix Christopher**
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HCRTEMC_TEM-1129_Jun-08-2016

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327



Calibration Data Record

TEM Consulting LP Radial T Coil Probe for Model No.: Radial T Coil Probe Serial No.: TEM-1129
Company : PCTEST Engineering Lab.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. dBV/A/m	-60.57		
2.0	Probe Level Linearity				
3.0	Probe Frequency Response				

Instruments used for calibration:				Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N	36064102	1-Oct-2015	,287708	1-Oct-2016
HP	34401A	S/N	36102471	1-Oct-2015	,287708	1-Oct-2016
HP	33120A	S/N	36043716	1-Oct-2015	,287708	1-Oct-2016
B&K	2133	S/N	1583254	1-Oct-2015	683/284413-14	1-Oct-2016



Cal. Date: 8-Jun-2016 Tested by: Felix Christopher
Calibrated on WCCL system type 9700
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11. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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